FCC ID: 2APXUES-CS20M

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)] $\sqrt{f(GHZ)}$ ≤ 3.0 for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- f(GHZ) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BLE:

| Modulation | Channel Freq. (GHz) | Conduct ed power (dBm) | Conducta | Tune-up power (dBm) | Max tune-up power (dBm) | Max tune-up power (mW) | Distance (mm) | Result calculation | SAR Exclusion threshold | SAR test exclusion |
|------------|---------------------------|------------------------------|----------|---------------------------|----------------------------------|---------------------------------|------------------|--------------------|-------------------------------|--------------------|
| GFSK | 2.402 | -2.17 | 0.61 | -2±1 | -1 | 0.79 | <5 | 0.24622 | 3.00 | YES |
| | 2.440 | -2.25 | 0.60 | -2±1 | -1 | 0.79 | <5 | 0.24816 | 3.00 | YES |
| | 2.480 | -2.37 | 0.58 | -2±1 | -1 | 0.79 | <5 | 0.25018 | 3.00 | YES |
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Conclusion:

For the max result: 0.25018W/Kg ≤ 3.0 for 1g SAR, No SAR is required.

Jason chen

Signature:

Date: 2018-06-6

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